

SURFACE IMPEDANCE OF MULTILAYERED SUPERCONDUCTING CAVITIES

DESY-TEMF July 2025

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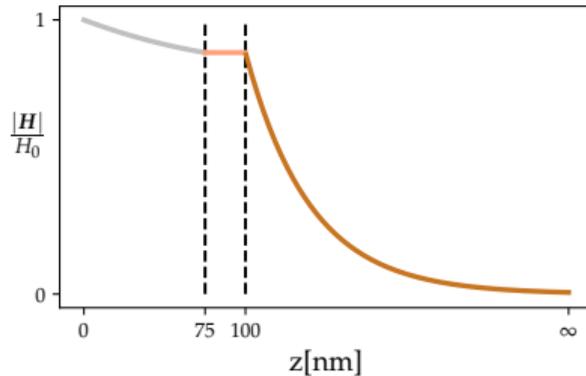
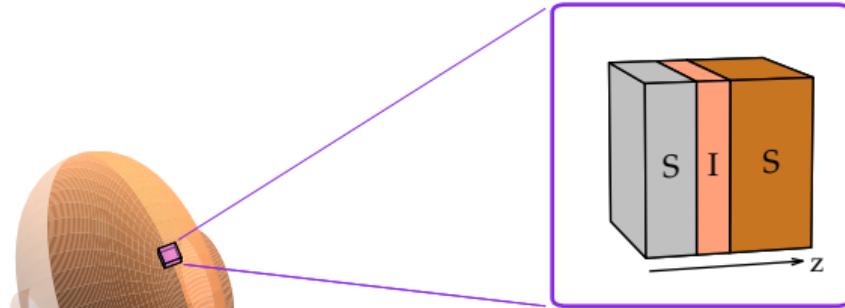
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Current Progress & Future Work

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MOTIVATION

Section 1



Why ?*

1. Niobium is expensive
2. Increase in energy efficiency
3. Higher accelerating fields

How ?

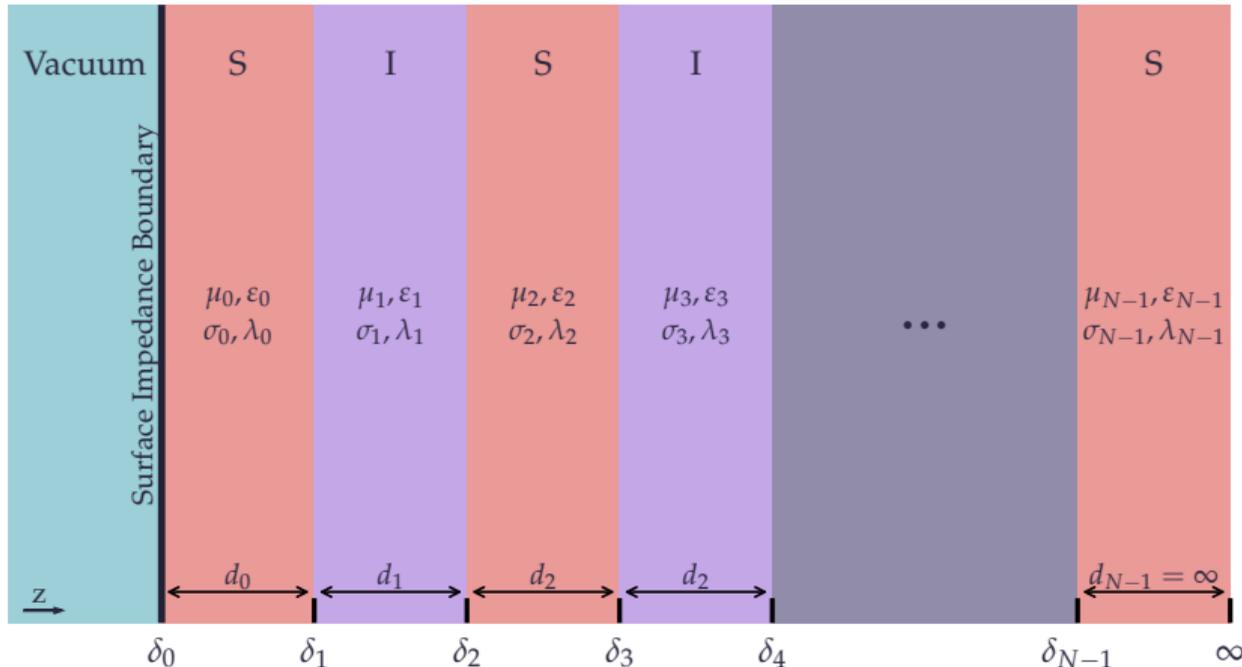
1. Replace bulk Nb with Cu, Al, etc. substrates
2. Better thermal conducting substrate
3. Shield with higher H_c material

* Valente-Feliciano, A.-M. *Superconductor Science and Technology* (2016)

REDUCTION TO SIBC

Section 2

ANALYTICAL SOLUTION



Solve Maxwell's equations in every layer $k \in \{0, \dots, N-1\}$:

$$E_x^{(k)} = \begin{pmatrix} C_{2k} \\ C_{2k+1} \end{pmatrix} \cdot \begin{pmatrix} e^{j\alpha_k z} \\ e^{-j\alpha_k z} \end{pmatrix} := \mathbf{C}_k \cdot \mathbf{u}_k$$

$$H_y^{(k)} = -\frac{\alpha_k}{\omega\mu_k} \begin{pmatrix} C_{2k} \\ C_{2k+1} \end{pmatrix} \cdot \begin{pmatrix} e^{j\alpha_k z} \\ -e^{-j\alpha_k z} \end{pmatrix} := -\frac{\alpha_k}{\omega\mu_k} \mathbf{C}_k \cdot \mathbf{v}_k$$

where $\alpha \in \mathbb{C}$ depends on material type:

$$\text{Insulator} : \alpha^2 = \mu\epsilon\omega^2$$

$$\text{Normal Conductor} : \alpha^2 = \mu\epsilon\omega^2 - j\mu\sigma\omega$$

$$\text{Superconductor (two-fluid)} : \alpha^2 = \mu\epsilon\omega^2 - j\mu\sigma\omega - \frac{1}{\lambda^2}$$

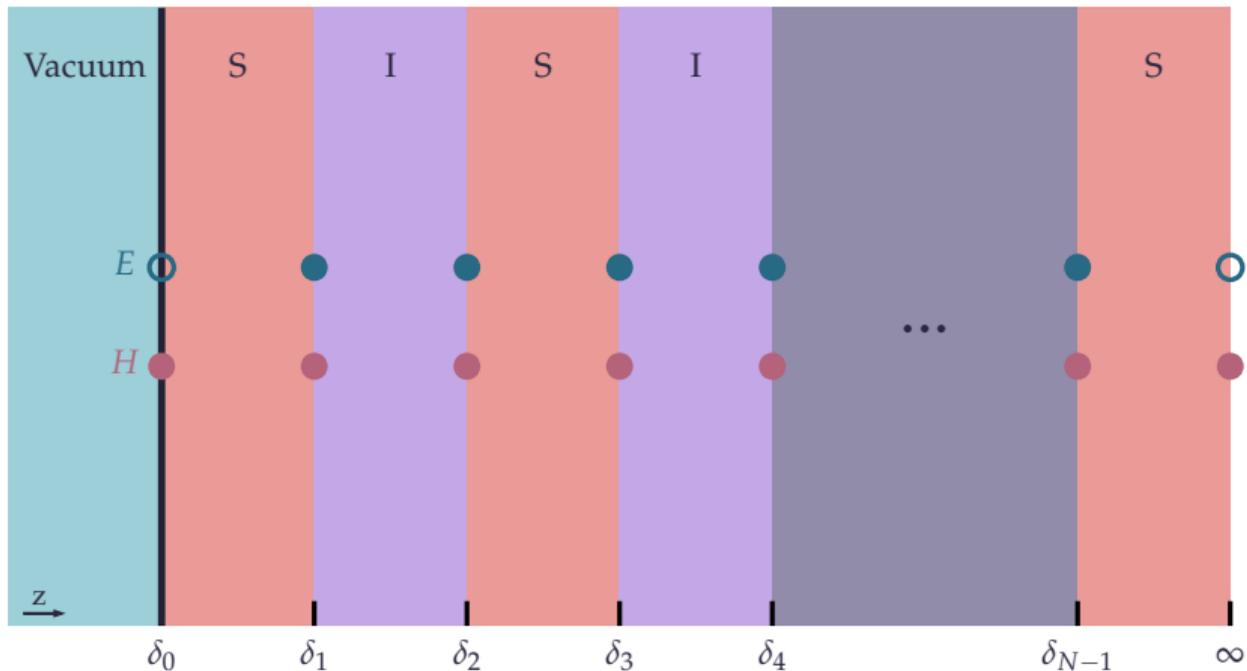
Surface impedance boundary condition

$$\mathbf{n} \times \mathbf{E} = Z(\mathbf{n} \times (\mathbf{n} \times \mathbf{H}))$$

yields surface impedance

$$Z(\omega) = \frac{E_x^{(0)}(\delta_0)}{H_y^{(0)}(\delta_0)} = -\frac{\omega\mu_0}{\alpha_0} \frac{\mathbf{C}_0 \cdot \mathbf{u}(\delta_0)}{\mathbf{C}_0 \cdot \mathbf{v}(\delta_0)}$$

⇒ We need the coefficient vector \mathbf{C}_0



$2N$ Unknowns = 1 vacuum constraint + $2(N - 1)$ interface constraints + 1 infinity constraint

Mathematically the constraints are:

- Vacuum constraint:

$$H_y^{(0)}(\delta_0) = H_0$$

- Interface constraints:

$$E_x^{(k)}(\delta_{k+1}) = E_x^{(k+1)}(\delta_{k+1})$$

$$H_y^{(k)}(\delta_{k+1}) = H_y^{(k+1)}(\delta_{k+1})$$

- Infinity constraint:

$$\lim_{z \rightarrow \infty} H_y^{(N-1)}(z) = 0$$

Implied relations between coefficients:

- Vacuum constraint:

$$\mathbf{C}_0 \cdot \begin{pmatrix} 1 \\ -1 \end{pmatrix} = -\frac{\omega\mu_0}{\alpha_0} H_0$$

- Interface constraints:

$$\mathbf{C}_k \cdot \mathbf{u}_k(\delta_{k+1}) = \mathbf{C}_{k+1} \cdot \mathbf{u}_{k+1}(\delta_{k+1})$$

$$\mathbf{C}_k \cdot \mathbf{v}_k(\delta_{k+1}) = \gamma_k \mathbf{C}_{k+1} \cdot \mathbf{v}_{k+1}(\delta_{k+1}), \quad \gamma_k = \frac{\mu_k}{\mu_{k+1}} \frac{\alpha_{k+1}}{\alpha_k}$$

- Infinity constraint:

$$\mathbf{C}_{N-1} = \mathbf{C} \begin{pmatrix} 1 \\ 0 \end{pmatrix}$$

Recursion relations via linear combination of interface constraints:

$$\mathbf{C}_k \cdot \begin{pmatrix} 1 \\ 0 \end{pmatrix} = \frac{1}{2} e^{-j\alpha_k \delta_{k+1}} \mathbf{C}_{k+1} \cdot (\Gamma_k \mathbf{u}_{k+1}(\delta_{k+1})), \quad \Gamma_k = \text{diag}(1 + \gamma_k, 1 - \gamma_k)$$

$$\mathbf{C}_k \cdot \begin{pmatrix} 0 \\ 1 \end{pmatrix} = \frac{1}{2} e^{j\alpha_k \delta_{k+1}} \mathbf{C}_{k+1} \cdot (\Gamma_k^\tau \mathbf{u}_{k+1}(\delta_{k+1})), \quad \Gamma_k^\tau = \text{diag}(1 - \gamma_k, 1 + \gamma_k)$$

yields characteristic matrix equation for each layer:

$$\mathbf{C}_k = \tau_{k,k+1} \mathbf{C}_{k+1}, \quad \tau_{k,k+1} = \frac{1}{2} \begin{pmatrix} e^{-j\alpha_k \delta_{k+1}} [\Gamma_k \mathbf{u}_{k+1}(\delta_{k+1})]^T \\ e^{j\alpha_k \delta_{k+1}} [\Gamma_k^\tau \mathbf{u}_{k+1}(\delta_{k+1})]^T \end{pmatrix}$$

and consequently a single transfer matrix:

$$\mathbf{C}_0 = T \mathbf{C}_{N-1} := \left[\prod_{k=0}^{N-2} \tau_{k,k+1} \right] \mathbf{C}_{N-1}$$

Now notice:

$$\mathbf{C}_0 = T\mathbf{C}_{N-1} = CT \begin{pmatrix} 1 \\ 0 \end{pmatrix} = C \begin{pmatrix} T_{00} \\ T_{01} \end{pmatrix}$$

So we find the surface impedance:

$$Z(\omega) = -\frac{\omega\mu_0}{\alpha_0} \frac{T_{00} + T_{01}}{T_{00} - T_{01}}$$

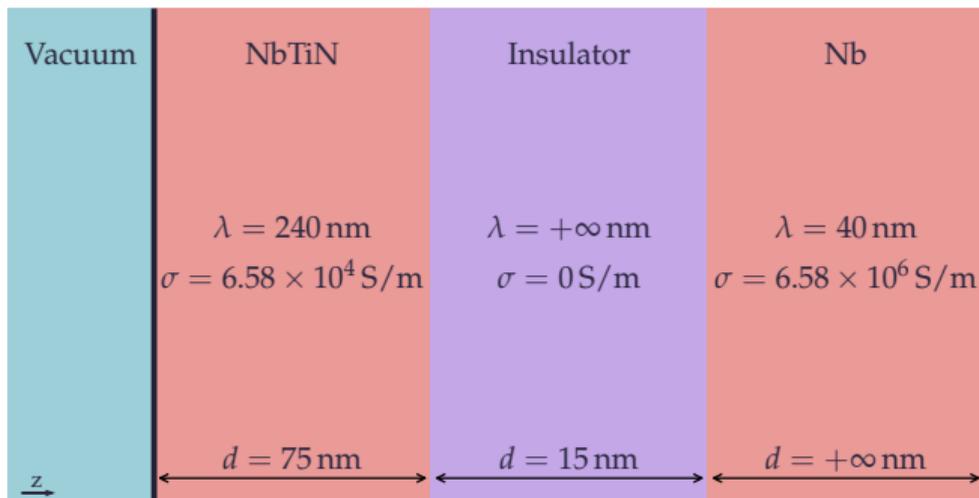
- $Z(\omega)$ is determined by transfer matrix, which we can compute
- $Z(\omega)$ is a non-linear function of ω
- **Difficulty:** Eigenvalueproblem is complex and non-linear

SELF-CONSISTENCY

- ✓ Surface impedance uses all material parameters from all layers
- ✓ Reduces to bulk superconductor formula when $N = 1$
- ✓ Reduces to bulk formula when all layers are identical

EXAMPLE

Bulk Nb with generic insulator layer and NbTiN sputtering at $f = 1.3 \text{ GHz}^*$



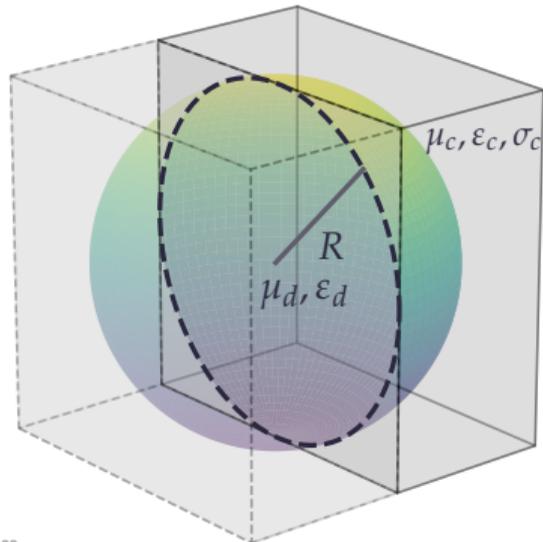
$$Z(\omega) = 21.462 \times 10^{-9} \Omega + 1.225 \times 10^{-3} j \Omega$$

* Keckert S., *PhD Dissertation, Universität Siegen (2020)*

CURRENT PROGRESS & FUTURE WORK

Section 3

LOSSY SPHERICAL RESONATOR*



Transcendental equation for TM_{mnp} modes

$$\eta_d \left[\frac{j_{n-1}(\beta_d R)}{j_n(\beta_d R)} - \frac{n}{\beta_d R} \right] - \eta_c \left[\frac{h_{n-1}^{(2)}(\beta_c R)}{h_n^{(2)}(\beta_c R)} - \frac{n}{\beta_c R} \right] = 0$$

where

$$\eta_d = \sqrt{\frac{\mu_d}{\varepsilon_d}}, \beta_d = \omega \sqrt{\mu_d \varepsilon_d},$$

$$\eta_c = \sqrt{\frac{\mu_c}{\varepsilon_c}}, \beta_c = \omega \sqrt{\mu_c \varepsilon_c},$$

* Papantonis S. et al., *Progress in Electromagnetics Research* (2015)

SEARCH FOR SOFTWARE

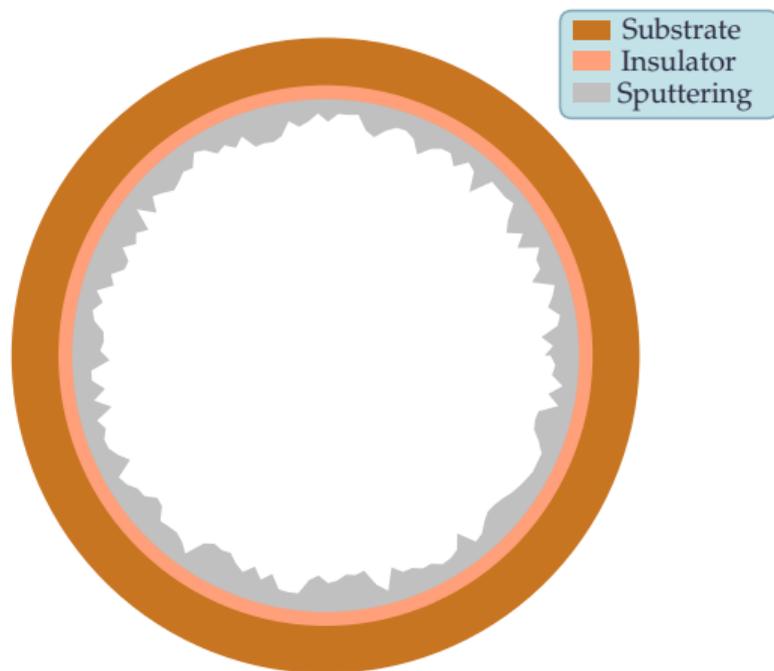
Software	Pros	Cons
CST	<ul style="list-style-type: none"> ▪ Reliable ▪ Easy to use 	<ul style="list-style-type: none"> ▪ Limited access to base structures ▪ Convergence difficulties when $Q \geq 10^{11}$
GetDP	<ul style="list-style-type: none"> ▪ Open source ▪ More access than CST 	<ul style="list-style-type: none"> ▪ SLEPc is difficult to tune ▪ *.pro files become difficult for complicated problems
FEniCSx	<ul style="list-style-type: none"> ▪ Open source ▪ More access than GetDP 	<ul style="list-style-type: none"> ▪ SLEPc is difficult to tune ▪ Steep learning curve
CEM-3D	<ul style="list-style-type: none"> ▪ Developed for RF cavities ▪ Custom eigensolver 	<ul style="list-style-type: none"> ▪ Proprietary ▪ Requires bug fix

FUTURE WORK

Study global surface impedance from multilayer computation

- Decide on which software to use
- Check that the result is stable across multiple iterations
- Check that it reduces to bulk result in appropriate limits

Study effects of sputtering distributions



- Thickness of sputtered layer becomes stochastic
- Model sputtering with Karhunen-Loève expansion
- $Z(\omega) \rightarrow Z(\omega, \mathbf{r})$
- Software must provide fine control
- Eigenvalues must have sufficient precision

CONCLUSION

Section 4

CONCLUSION

- Multilayered cavities can be modelled via SIBC
- Resulting eigenvalue problem is complex and non-linear
- Software must allow sufficient control to model sputtering
- Eigensolver must have sufficient precision to see sputtering effects